# 2.5V/3.3V SiGe 1:2 Differential Clock Driver with RSECL\* Outputs

# \*Reduced Swing ECL

## **Description**

The NBSG11 is a 1-to-2 differential fanout buffer, optimized for low skew and Ultra-Low JITTER.

Inputs incorporate internal 50  $\Omega$  termination resistors and accept NECL (Negative ECL), PECL (Positive ECL), CML, LVCMOS, LVTTL, or LVDS. Outputs are RSECL (Reduced Swing ECL), 400 mV.

#### **Features**

- Maximum Input Clock Frequency up to 12 GHz Typical
- Maximum Input Data Rate up to 12 Gb/s Typical
- 30 ps Typical Rise and Fall Times
- 125 ps Typical Propagation Delay
- RSPECL Output with Operating Range: V<sub>CC</sub> = 2.375 V to 3.465 V with V<sub>EE</sub> = 0 V
- RSNECL Output with RSNECL or NECL Inputs with Operating Range: V<sub>CC</sub> = 0 V with V<sub>EE</sub> = -2.375 V to -3.465 V
- RSECL Output Level (400 mV Peak-to-Peak Output), Differential Output Only
- 50  $\Omega$  Internal Input Termination Resistors
- Compatible with Existing 2.5 V/3.3 V LVEP, EP, and LVEL Devices
- Pb-Free Packages are Available



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#### **MARKING DIAGRAMS\***



FCBGA-16 BA SUFFIX CASE 489





FCLGA-16 MA SUFFIX CASE 526





QFN-16 MN SUFFIX CASE 485G



A = Assembly Location

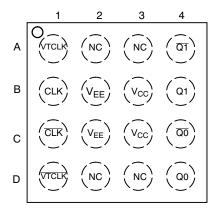
L = Wafer Lot
Y = Year
W = Work Week
= Pb-Free Package

(Note: Microdot may be in either location)

\*For additional marking information, refer to Application Note AND8002/D.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 10 of this data sheet.



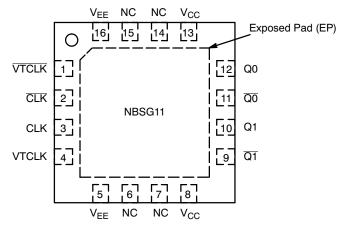


Figure 1. BGA-16 and LGA-16 Pinout (Top View)

Figure 2. QFN-16 Pinout (Top View)

**Table 1. PIN DESCRIPTION** 

Pin				
BGA	QFN	Name	I/O	Description
D1	1	VTCLK	-	Internal 50 $\Omega$ Termination Pin. See Table 2.
C1	2	CLK	ECL, CML, LVCMOS, LVDS, LVTTL Input	Inverted Differential Input. Internal 75 k $\Omega$ to $V_{EE}$ and 36.5 k $\Omega$ to $V_{CC}.$
B1	3	CLK	ECL, CML, LVCMOS, LVDS, LVTTL Input	Noninverted Differential Input. Internal 75 k $\Omega$ to V <sub>EE</sub> .
A1	4	VTCLK	-	Internal 50 $\Omega$ Termination Pin. See Table 2.
B2,C2	5,16	V <sub>EE</sub>	-	Negative Supply Voltage
A2,A3,D2, D3	6,7,14,15	NC	-	No Connect
B3,C3	8,13	V <sub>CC</sub>	-	Positive Supply Voltage
A4	9	Q1	RSECL Output	Inverted Differential Output 1. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> - 2.0 V.
B4	10	Q1	RSECL Output	Noninverted Differential Output 1. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2.0 V.
C4	11	Q0	RSECL Output	Inverted Differential output 0. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2.0 V.
D4	12	Q0	RSECL Output	Noninverted Differential Output 0. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2 V.
N/A	-	EP	-	Exposed Pad (Note 2)

- 1. The NC pins are electrically connected to the die and must be left open.
- 2. All V<sub>CC</sub> and V<sub>EE</sub> pins must be externally connected to Power Supply to guarantee proper operation. The thermally exposed pad on package
- bottom (see case drawing) must be attached to a heat-sinking conduit.

  In the differential configuration when the input termination pins (VTCLK, VTCLK) are connected to a common termination voltage, and if no signal is applied then the device will be susceptible to self-oscillation.

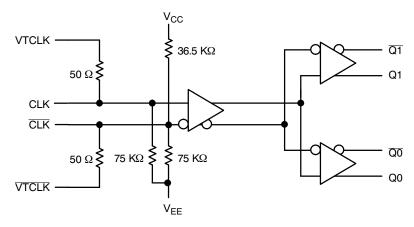


Figure 3. Logic Diagram

# **Table 2. INTERFACING OPTIONS**

INTERFACING OPTIONS	CONNECTIONS
CML	Connect VTCLK and VTCLK to V <sub>CC</sub>
LVDS	Connect VTCLK and VTCLK together
AC-COUPLED	Bias VTCLK and VTCLK Inputs within (VIHCMR) Common Mode Range
RSECL, PECL, NECL	Standard ECL Termination Techniques
LVTTL, LVCMOS	An external voltage should be be applied to the unused complementary differential input.  Nominal voltage is 1.5 V for LVTTL and V <sub>CC</sub> /2 for LVCMOS inputs.

# **Table 3. ATTRIBUTES**

Characterist	tics	Value					
Internal Input Pulldown Resistor (CLK	75 kΩ						
Internal Input Pullup Resistor (CLK)	36.5	ikΩ					
ESD Protection	> 2 kV > 100 V						
Moisture Sensitivity (Note 4)	Pb Pkg	Pb-Free Pkg					
	FCLGA-16, FCBGA-16 QFN-16	Level 3 Level 1	Level 3 Level 1				
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in					
Transistor Count	125						
Meets or exceeds JEDEC Spec EIA/J	Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test						

<sup>4.</sup> For additional information, see Application Note AND8003/D.

**Table 4. MAXIMUM RATINGS** 

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V <sub>CC</sub>	Positive Power Supply	V <sub>EE</sub> = 0 V		3.6	V
V <sub>EE</sub>	Negative Power Supply	V <sub>CC</sub> = 0 V		-3.6	V
VI	Positive Input Negative Input	V <sub>EE</sub> = 0 V V <sub>CC</sub> = 0 V	$\begin{aligned} &V_I \leq V_{CC} \\ &V_I \geq V_{EE} \end{aligned}$	3.6 -3.6	V V
V <sub>INPP</sub>	Differential Input Voltage  D - D	$\begin{array}{ccc} V_{CC} - V_{EE} \geq & 2.8 \ V \\ V_{CC} - V_{EE} < & 2.8 \ V \end{array}$		2.8  V <sub>CC</sub> - V <sub>EE</sub>	V V
l <sub>out</sub>	Output Current	Continuous Surge		25 50	mA mA
T <sub>A</sub>	Operating Temperature Range	16 FCBGA, FCLGA 16 QFN		-40 to +70 -40 to +85	°C
T <sub>stg</sub>	Storage Temperature Range			-65 to +150	°C
θ <sub>JA</sub>	Thermal Resistance (Junction-to-Ambient) (Note 5)	0 Ifpm 500 Ifpm 0 Ifpm 500 Ifpm	16 FCBGA, FCLGA 16 FCBGA, FCLGA 16 QFN 16 QFN	108 86 41.6 35.2	°C/W °C/W °C/W °C/W
$\theta_{\sf JC}$	Thermal Resistance (Junction-to-Case)	1S2P (Note 5) 2S2P (Note 6)	16 FCBGA, FCLGA 16 QFN	5.0 4.0	°C/W °C/W
T <sub>sol</sub>	Wave Solder Pb-Free			225 265	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

5. JEDEC standard multilayer board – 1S2P (1 signal, 2 power).

6. JEDEC standard multilayer board – 2S2P (2 signal, 2 power) with 8 filled thermal vias under exposed pad.

Table 5. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT V<sub>CC</sub> = 2.5 V; V<sub>EE</sub> = 0 V (Note 7)

		-40°C				25°C		70°C(L0	(QFN)**		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
V <sub>OH</sub>	Output HIGH Voltage (Note 8)	1450	1530	1575	1525	1565	1600	1550	1590	1625	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Note 10)	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Note 11)	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 9)	1.2		2.5	1.2		2.5	1.2		2.5	V
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> , V <sub>IHMAX</sub> )		80	150		80	150		80	150	μΑ
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> , V <sub>ILMIN</sub> )		25	100		25	100		25	100	μΑ

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

<sup>\*</sup>Typicals used for testing purposes.

<sup>\*\*</sup>The device packaged in FCLGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

<sup>7.</sup> Input and output parameters vary 1:1 with V<sub>CC</sub>. V<sub>EE</sub> can vary +0.125 V to -0.965 V. 8. All loading with 50  $\Omega$  to V<sub>CC</sub> - 2.0 V. V<sub>OH</sub>/V<sub>OL</sub> measured at V<sub>IH</sub>/V<sub>IL</sub>.

<sup>9.</sup> VIHCMR min varies 1:1 with VEE, VIHCMR max varies 1:1 with VCC. The VIHCMR range is referenced to the most positive side of the differential input signal.

<sup>10.</sup> VIH cannot exceed VCC.

<sup>11.</sup>  $V_{IL}$  always  $\geq V_{EE}$ .

Table 6. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT V<sub>CC</sub> = 3.3 V; V<sub>EE</sub> = 0 V (Note 12)

			-40°C			25°C		70°C(L0	(QFN)**		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
V <sub>OH</sub>	Output HIGH Voltage (Note 13)	2250	2330	2375	2325	2365	2400	2350	2390	2425	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Note 15)	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Note 16)	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	٧
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Note 14) (Differential Configuration)	1.2		3.3	1.2		3.3	1.2		3.3	V
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> , V <sub>IHMAX</sub> )		80	150		80	150		80	150	μΑ
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> , V <sub>ILMIN</sub> )		25	100		25	100		25	100	μΑ

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

<sup>12.</sup> Input and output parameters vary 1:1 with  $V_{CC}$ .  $V_{EE}$  can vary +0.925 V to -0.165 V.

13. All loading with 50  $\Omega$  to  $V_{CC}$  - 2.0 V.  $V_{OH}/V_{OL}$  measured at  $V_{IH}/V_{IL}$ .

14.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ ,  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential

<sup>15.</sup> V<sub>IH</sub> cannot exceed V<sub>CC</sub>.

<sup>16.</sup>V<sub>IL</sub> always ≥ V<sub>EE</sub>. \*Typicals used for testing purposes.

<sup>\*\*</sup>The device packaged in FCLGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

### Table 7. DC CHARACTERISTICS, NECL OR RSNECL INPUT WITH NECL OUTPUT

 $V_{CC} = 0 \text{ V}; V_{EE} = -3.465 \text{ V to } -2.375 \text{ V (Note 17)}$ 

			-40°C			25°C		70°C(L0	(QFN)**		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
VOH	Output HIGH Voltage (Note 18)	-1050	-970	-925	-975	-935	-900	-950	-910	-875	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage	350	410	525	350	410	525	350	410	525	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Note 20)	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V <sub>CC</sub> - 1435 mV	V <sub>CC</sub> - 1000 mV*	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Note 21)	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V <sub>IH</sub> - 2.5 V	V <sub>CC</sub> - 1400 mV*	V <sub>IH</sub> - 150 mV	V
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 19)	V <sub>EE</sub> -	+1.2	0.0	V <sub>EE</sub> -	+1.2	0.0	V <sub>EE</sub>	+1.2	0.0	V
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> , V <sub>IHMAX</sub> )		80	150		80	150		80	150	μА
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> , V <sub>ILMIN</sub> )		25	100		25	100		25	100	μΑ

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

<sup>17.</sup> Input and output parameters vary 1:1 with V<sub>CC</sub>. 18. All loading with 50  $\Omega$  to V<sub>CC</sub> – 2.0 V. V<sub>OH</sub>/V<sub>OL</sub> measured at V<sub>IH</sub>/V<sub>IL</sub>.

<sup>19.</sup> V<sub>IHCMR</sub> min varies 1:1 with V<sub>EE</sub>, V<sub>IHCMR</sub> max varies 1:1 with V<sub>CC</sub>. The V<sub>IHCMR</sub> range is referenced to the most positive side of the differential input signal.

<sup>20.</sup> VIH cannot exceed VCC.

<sup>21.</sup>V<sub>IL</sub> always ≥ V<sub>EE</sub>.

\*Typicals used for testing purposes.

\*\*The device packaged in FCLGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

### Table 8. AC CHARACTERISTICS for FCLGA-16

 $V_{CC} = 0 \text{ V}$ ;  $V_{EE} = -3.465 \text{ V}$  to -2.375 V or  $V_{CC} = 2.375 \text{ V}$  to 3.465 V;  $V_{EE} = 0 \text{ V}$ 

			-40°C			25°C			70°C		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>max</sub>	Maximum Frequency (See Figure 4. F <sub>max</sub> /JITTER) (Note 22)	10.709	12		10.709	12		10.709	12		GHz
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay to Output Differential	90	125	160	90	125	160	90	125	160	ps
t <sub>SKEW</sub>	Duty Cycle Skew (Note 23) Within-Device Skew (Note 24) Device-to-Device Skew (Note 25)		3 6 25	15 15 50		3 6 25	15 15 50		3 6 25	15 15 50	ps
t <sub>JITTER</sub>	RMS Random Clock Jitter  f <sub>in</sub> < 10 GHz  Peak-to-Peak Data Dependent Jitter  f <sub>in</sub> < 10 Gb/s		0.2 TBD	1		0.2 TBD	1		0.2 TBD	1	ps
V <sub>INPP</sub>	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 26)	75		2600	75		2600	75		2600	mV
t <sub>r</sub>	Output Rise/Fall Times Q, Q (20% - 80%) @ 1 GHz	20	30	55	20	30	55	20	30	55	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 23. See Figure 5. t<sub>SKEW</sub> = |t<sub>PLH</sub> t<sub>PHL</sub>| for a nominal 50% Differential Clock Input Waveform.
- 24. Within-Device skew is defined as identical transitions on similar paths through a device.
- 25. Device-to-device skew for identical transitions at identical  $V_{CC}$  levels.
- 26.  $V_{INPP}$  (MAX) cannot exceed  $V_{CC}$   $V_{EE}$ .

<sup>22.</sup> Measured using a 500 mV source, 50% duty cycle clock source. All loading with 50  $\Omega$  to  $V_{CC}$  – 2.0 V. For minimum f<sub>max</sub> value of 10.709 GHz, output amplitude is approximately 200 mV (as shown in Figure 4, where output P–P spec is shown as a minimum/guarantee of around 150 mV). Input edge rates 40 ps (20% – 80%).

Table 9. AC CHARACTERISTICS for QFN-16  $V_{CC} = 0 \text{ V}$ ;  $V_{EE} = -3.465 \text{ V}$  to -2.375 V or  $V_{CC} = 2.375 \text{ V}$  to 3.465 V;  $V_{EE} = 0 \text{ V}$ 

			-40°C			25°C			85°C		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>max</sub>	Maximum Frequency (See Figure 4. F <sub>max</sub> /JITTER) (Note 27)	10.5	12		10.5	12		10.5	12		GHz
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay to Output Differential	90	125	160	90	125	160	90	125	160	ps
t <sub>SKEW</sub>	Duty Cycle Skew (Note 28) Within-Device Skew (Note 29) Device-to-Device Skew (Note 30)		3 6 25	15 15 50		3 6 25	15 15 50		3 6 25	15 15 50	ps
<sup>†</sup> JITTER	RMS Random Clock Jitter		0.2 TBD	1		0.2 TBD	1		0.2 TBD	1	ps
V <sub>INPP</sub>	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 31)	75		2600	75		2600	75		2600	mV
t <sub>r</sub>	Output Rise/Fall Times Q, Q (20% - 80%) @ 1 GHz	15	30	55	20	30	55	20	30	55	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- 28. See Figure 5. t<sub>SKEW</sub> = |t<sub>PLH</sub> t<sub>PHL</sub>| for a nominal 50% Differential Clock Input Waveform.
- 29. Within-Device skew is defined as identical transitions on similar paths through a device.
- 30. Device-to-device skew for identical transitions at identical V<sub>CC</sub> levels.
- 31. $V_{INPP}$  (MAX) cannot exceed  $V_{CC}$   $V_{EE}$ .

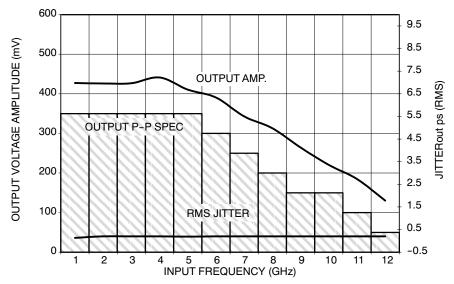


Figure 4. Output Voltage Amplitude (V<sub>OUTPP</sub>) / RMS Jitter vs. Input Frequency (f<sub>in</sub>) at Ambient Temperature (Typical)

<sup>27.</sup> Measured using a 500 mV source, 50% duty cycle clock source. All loading with 50  $\Omega$  to  $V_{CC}$ -2.0 V. For minimum  $f_{max}$  value of 10.5 GHz, output amplitude is approximately 200 mV (as shown in Figure 4, where output P-P spec is shown as a minimum/guarantee of around 150 mV). Input edge rates 40 ps (20% - 80%).

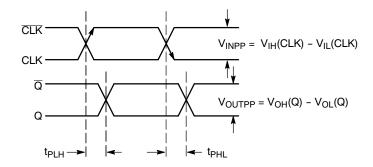


Figure 5. AC Reference Measurement

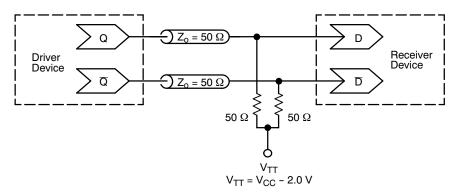


Figure 6. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

# **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>			
NBSG11BA	FCBGA-16	100 Units / Tray (Contact Sales Representative)			
NBSG11BAR2	FCBGA-16	100 / Tape & Reel (Contact Sales Representative)			
NBSG11MAG	FCLGA-16, 4x4 mm (Pb-Free)	100 Units / Tray (Contact Sales Representative)			
NBSG11MAHTBG	FCLGA-16, 4x4 mm (Pb-Free)	100 / Tape & Reel			
NBSG11MN	QFN-16	123 Units / Rail			
NBSG11MNG	QFN-16 (Pb-Free)	123 Units / Rail			
NBSG11MNR2	QFN-16	3000 / Tape & Reel			
NBSG11MNR2G	QFN-16 (Pb-Free)	3000 / Tape & Reel			

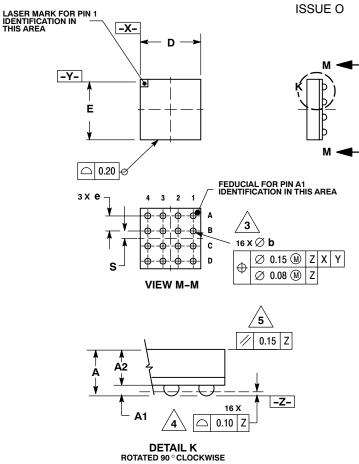
Board	Description
NBSG11BAEVB	NBSG11BA Evaluation Board

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### **PACKAGE DIMENSIONS**

# FCBGA-16 **BA SUFFIX** PLASTIC 4X4 (mm) BGA FLIP CHIP PACKAGE

CASE 489-01

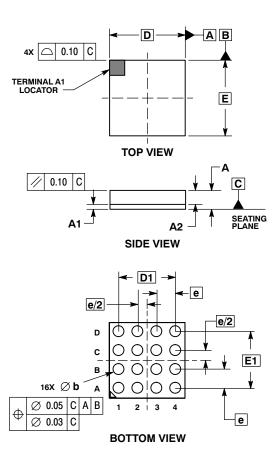


- NOTES:
  1. DIMENSIONS ARE IN MILLIMETERS.
  2. INTERPRET DIMENSIONS AND TOLERANCES
  PER ASME Y14.5M, 1994.
  3. DIMENSION b IS MEASURED AT THE MAXIMUM
  SOLDER BALL DIAMETER, PARALLEL TO DATUM
  PLANE Z.
  4. DATUM Z (SEATING PLANE) IS DEFINED BY THE
  SPHERICAL CROWNS OF THE SOLDER BALLS.
  5. PARALLELISM MEASUREMENT SHALL EXCLUDE
  ANY EFFECT OF MARK ON TOP SURFACE OF
  PACKAGE.

	MILLIMETERS							
DIM	MIN	MAX						
Α	1.40 MAX							
A1	0.25	0.35						
A2	1.20 REF							
b	0.30	0.50						
D	4.00	BSC						
Е	4.00	BSC						
е	1.00	BSC						
S	0.50	BSC						

# **PACKAGE DIMENSIONS**

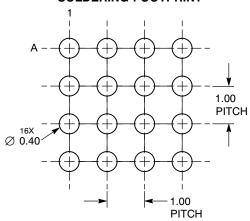
16 PIN LGA 4x4, 1.0P CASE 526AB-01 ISSUE C



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS		
DIM	MIN	TYP	MAX
Α	0.89	0.96	1.03
A1	0.22	0.26	0.30
A2	0.67	0.70	0.73
b	0.30	0.40	0.50
D	4.00 BSC		
D1	3.00 BSC		
E	4.00 BSC		
E1	3.00 BSC		
e	1.00 BSC		

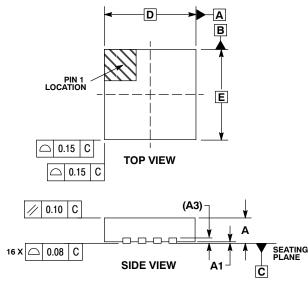
# **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

### 16 PIN QFN CASE 485G-01 ISSUE C



D2

16

16X b

е

13

**BOTTOM VIEW** 

EXPOSED PAD

E2

е

16X L

16X K

С A B

0.10

0.05 С NOTE 3

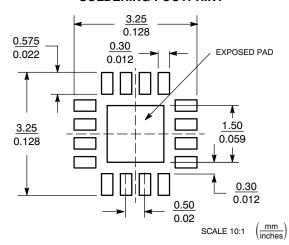
NOTE 5

#### NOTES

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
- CONTROLLING DIMENSION: MILLIMETERS. DIMENSION 6 APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS. Lmax CONDITION CAN NOT VIOLATE 0.2 MM MINIMUM SPACING BETWEEN LEAD TIP AND ELAC.
- AND FLAG

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.80	1.00	
A1	0.00	0.05	
А3	0.20 REF		
b	0.18	0.30	
D	3.00 BSC		
D2	1.65	1.85	
E	3.00 BSC		
E2	1.65	1.85	
е	0.50 BSC		
K	0.18 TYP		
L	0.30	0.50	

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and solder details, please download the ON Semiconductor Soldering a Mounting Techniques Reference Manual, SOLDERRM/D.

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